



# ACE8212B

## Common Drain N-Channel Enhancement Mode Field Effect Transistor with ESD

### Description

The ACE8212B uses advanced trench technology to provide excellent  $R_{DS(ON)}$  and low gate charge. They offer operation over a wide gate drive range from 1.8V to 12V. It is ESD protected. This device is suitable for use as a uni-directional or bi-directional load switch, facilitated by its common-drain configuration.

### Features

- $V_{DS}(V)=20V$
- $I_D=8A$  ( $V_{GS}=10V$ )
- TSSOP-8
  - $R_{DS(ON)}<13\ m\Omega$  ( $V_{GS}=10V$ )
  - $R_{DS(ON)}<14\ m\Omega$  ( $V_{GS}=4.5V$ )
  - $R_{DS(ON)}<19\ m\Omega$  ( $V_{GS}=2.5V$ )
  - $R_{DS(ON)}<27\ m\Omega$  ( $V_{GS}=1.8V$ )
- DFN2\*5
  - $R_{DS(ON)}<13\ m\Omega$  ( $V_{GS}=10V$ )
  - $R_{DS(ON)}<16\ m\Omega$  ( $V_{GS}=4.5V$ )
  - $R_{DS(ON)}<22\ m\Omega$  ( $V_{GS}=2.5V$ )
  - $R_{DS(ON)}<35\ m\Omega$  ( $V_{GS}=1.8V$ )
- ESD Protected: 2000V

### Absolute Maximum Ratings

Parameter		Symbol	Max	Unit	
Drain-Source Voltage		$V_{DSS}$	20	V	
Gate-Source Voltage		$V_{GSS}$	$\pm 12$	V	
Continuous Drain Current *AC	$T_A=25^\circ C$	$I_D$	8	A	
	$T_A=70^\circ C$		6.4		
Pulsed Drain Current		$I_{DM}$	30	A	
Power Dissipation	TSSOP-8	$P_D$	$T_A=25^\circ C$	1.5	W
			$T_A=70^\circ C$	1	
	DFN2*5		$T_A=25^\circ C$	1.6	
			$T_A=70^\circ C$	1	
Operating Junction Temperature / Storage Temperature Range		$T_J/T_{STG}$	-55/150	$^\circ C$	

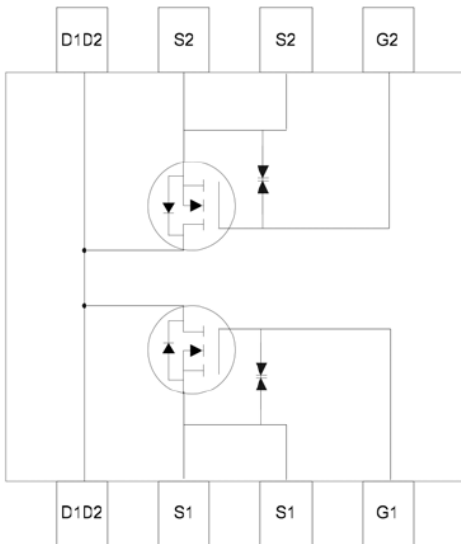


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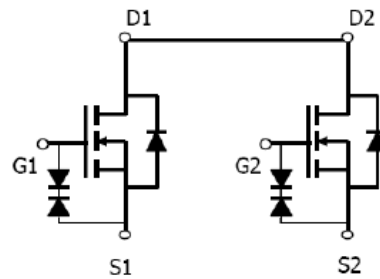
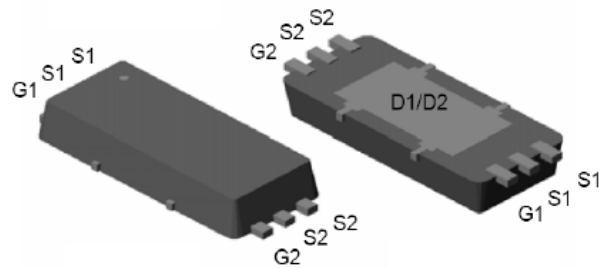
Common Drain N-Channel Enhancement Mode Field Effect Transistor with ESD

## Packaging Type

TSSOP-8

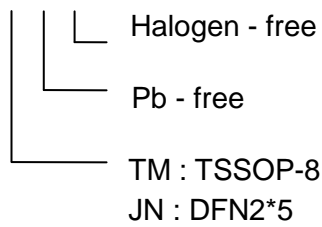


DFN2\*5



## Ordering information

ACE8212B XX + H





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### Electrical Characteristics

$T_A=25^{\circ}\text{C}$ , unless otherwise noted.

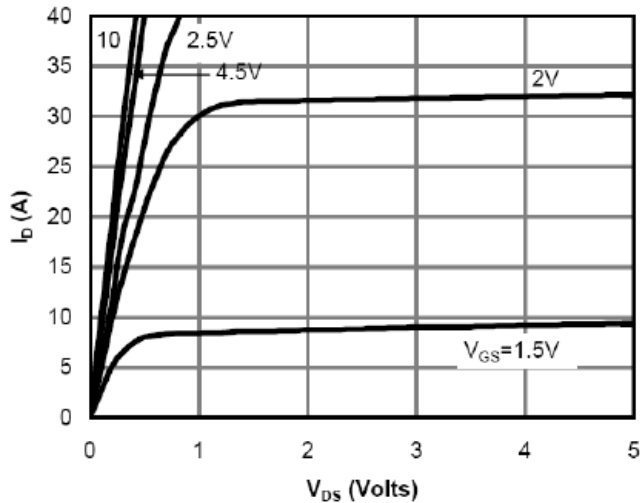
Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250\ \mu A$	20			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_{DS}=250\ \mu A$	0.5	0.72	1	
Gate Leakage Current	$I_{GSS}$	$V_{DS}=0V, V_{GS}=\pm 12V$			10	$\mu A$
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=20V, V_{GS}=0V$			1	$\mu A$
Maximum Body-Diode Continuous Current	$I_S$				2.4	A
Drain-Source On-Resistance (TSSOP-8)	$R_{DS(on)}$	$V_{GS}=10V, I_D=8A$		8.2	13	m $\Omega$
		$V_{GS}=4.5V, I_D=5A$		9.2	14	
		$V_{GS}=2.5V, I_D=4A$		12	19	
		$V_{GS}=1.8V, I_D=3A$		18	27	
Drain-Source On-Resistance (DFN2*5)	$R_{DS(on)}$	$V_{GS}=10V, I_D=8A$		10	13	m $\Omega$
		$V_{GS}=4.5V, I_D=7A$		11	16	
		$V_{GS}=2.5V, I_D=6A$		14	22	
		$V_{GS}=1.8V, I_D=4.5A$		21	35	
Forward Transconductance	$g_{fs}$	$V_{DS}=10V, I_D=8A$		30		S
Diode Forward Voltage	$V_{SD}$	$I_{SD}=1A, V_{GS}=0V$		0.72	1.0	V
Switching						
Total Gate Charge	$Q_g$	$V_{DS}=10V, V_{GS}=4.5V, I_D=8A$		4.65	6.05	nC
Gate-Source Charge	$Q_{gs}$			1.12	1.46	
Gate-Drain Charge	$Q_{gd}$			3.72	4.84	
Turn-On Time	$t_{d(on)}$	$V_{GS}=10V, R_L=10\ \Omega, V_{DS}=10V, R_{GEN}=3\ \Omega$		487.6	975.2	ns
	$t_r$			800.4	1600.8	
Turn-Off Time	$t_{d(off)}$			1728	3456	
	$t_f$			6180	12360	
Dynamic						
Input Capacitance	$C_{iss}$	$V_{GS}=0V, V_{DS}=10V, f=1\text{MHz}$		36.45		pF
Output Capacitance	$C_{oss}$			183.88		
REVERSE Transfer Capacitance	$C_{rss}$			14.57		



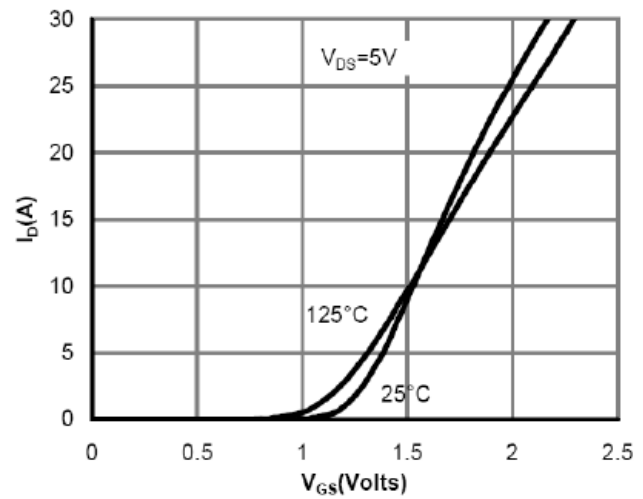
**Note:**

1. The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^{\circ}\text{C}$ . The value in any given application depends on the user's specific board design.
2. Repetitive rating, pulse width limited by junction temperature.
3. The current rating is based on the  $t \leq 10\text{s}$  junction to ambient thermal resistance rating.

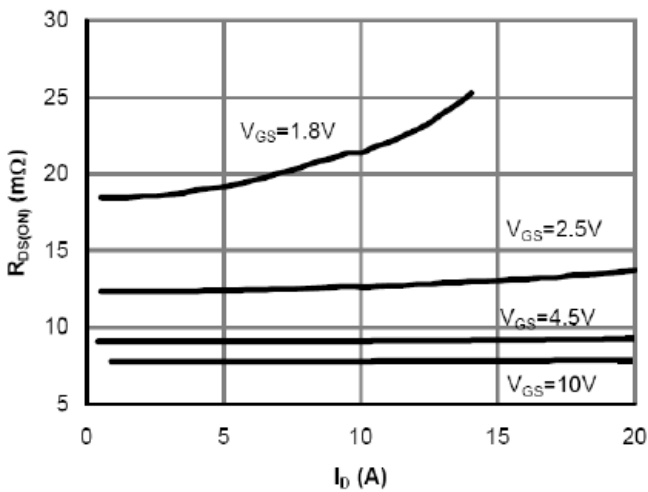
### Typical Performance Characteristics



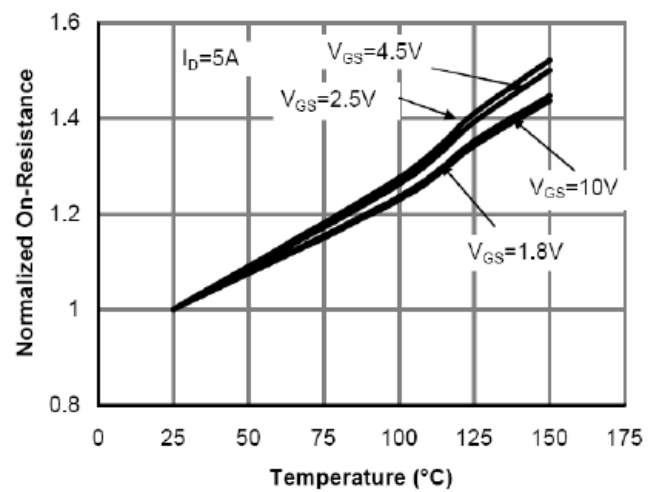
**Fig 1: On-Region Characteristics**



**Figure 2: Transfer Characteristics**



**Figure 3: On-Resistance vs. Drain Current and Gate Voltage**



**Figure 4: On-Resistance vs. Junction Temperature**



Typical Performance Characteristics

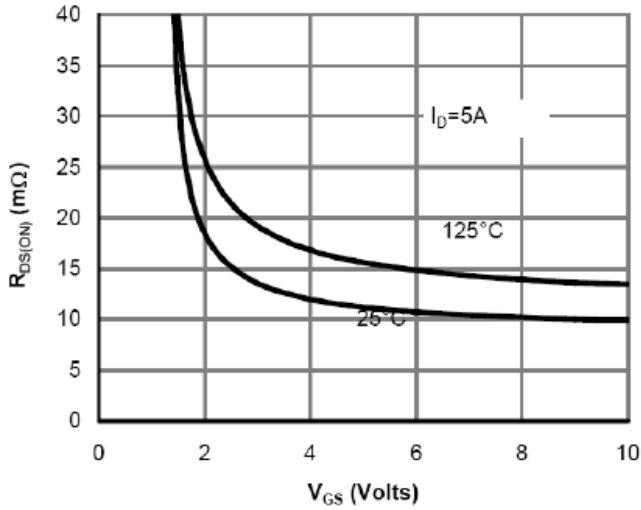


Figure 5: On-Resistance vs. Gate-Source Voltage

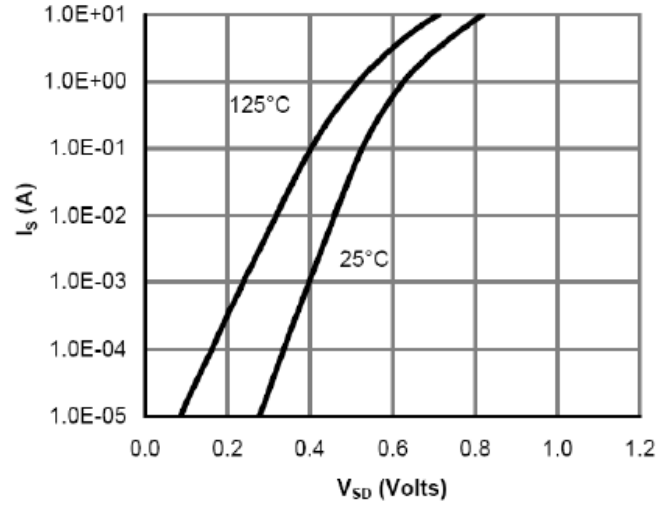


Figure 6: Body-Diode Characteristics

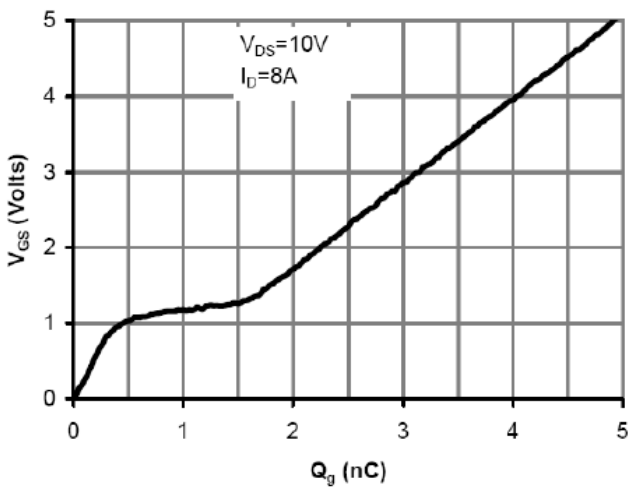


Figure 7: Gate-Charge Characteristics

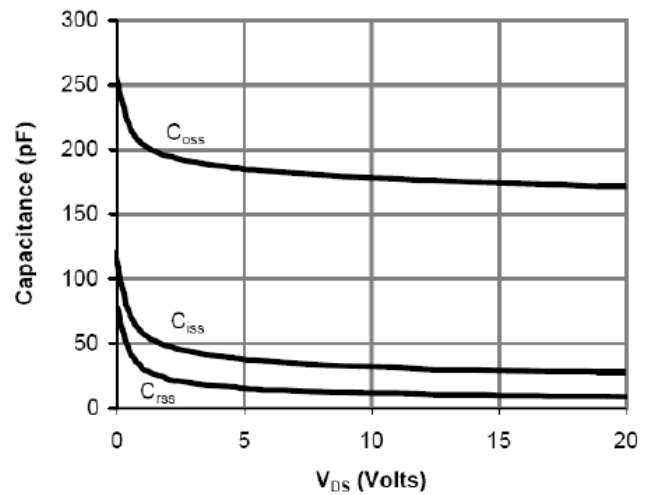


Figure 8: Capacitance Characteristics

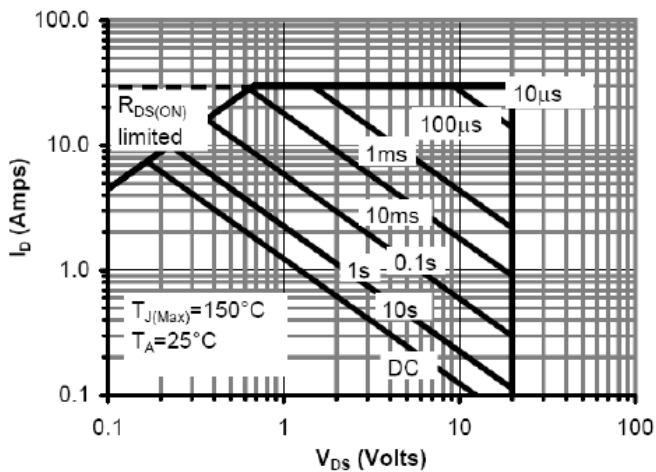


Figure 9: Maximum Forward Biased Safe Operating Area

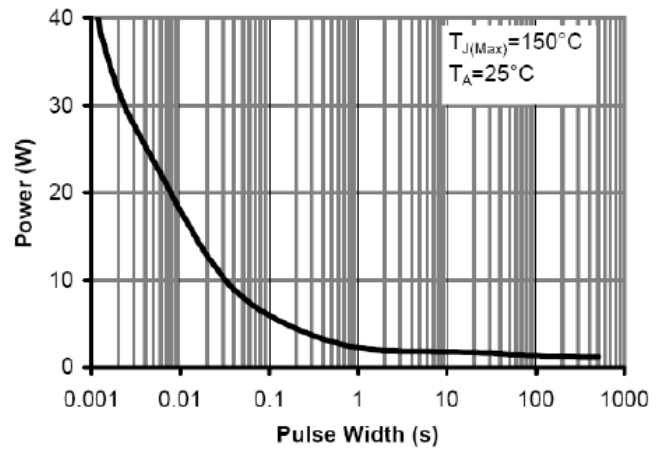


Figure 10: Single Pulse Power Rating Junction-to-Ambient



Typical Performance Characteristics

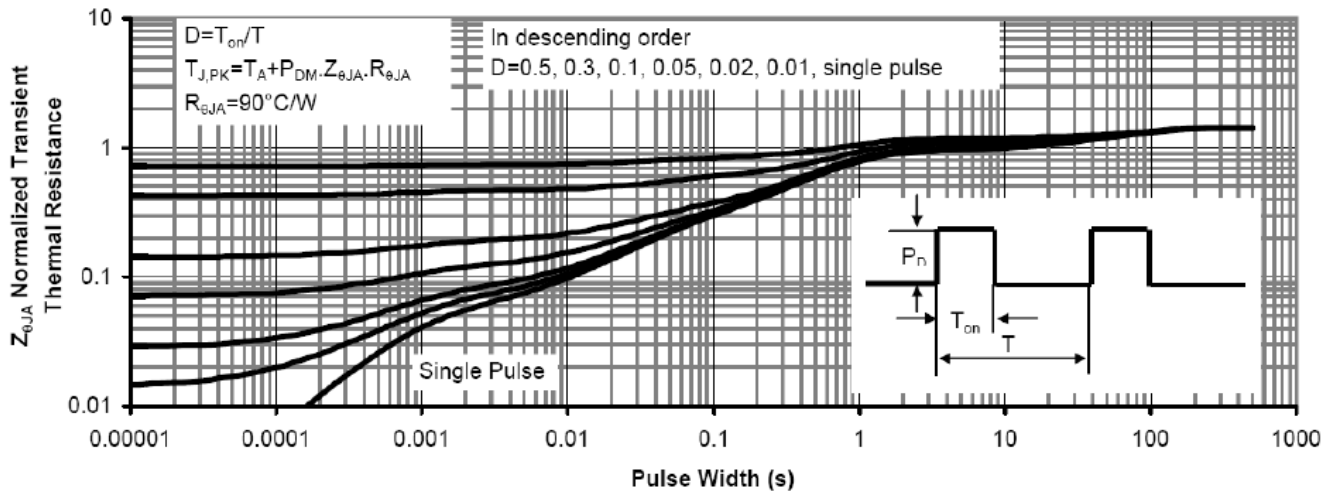


Figure 11: Normalized Maximum Transient Thermal Impedance

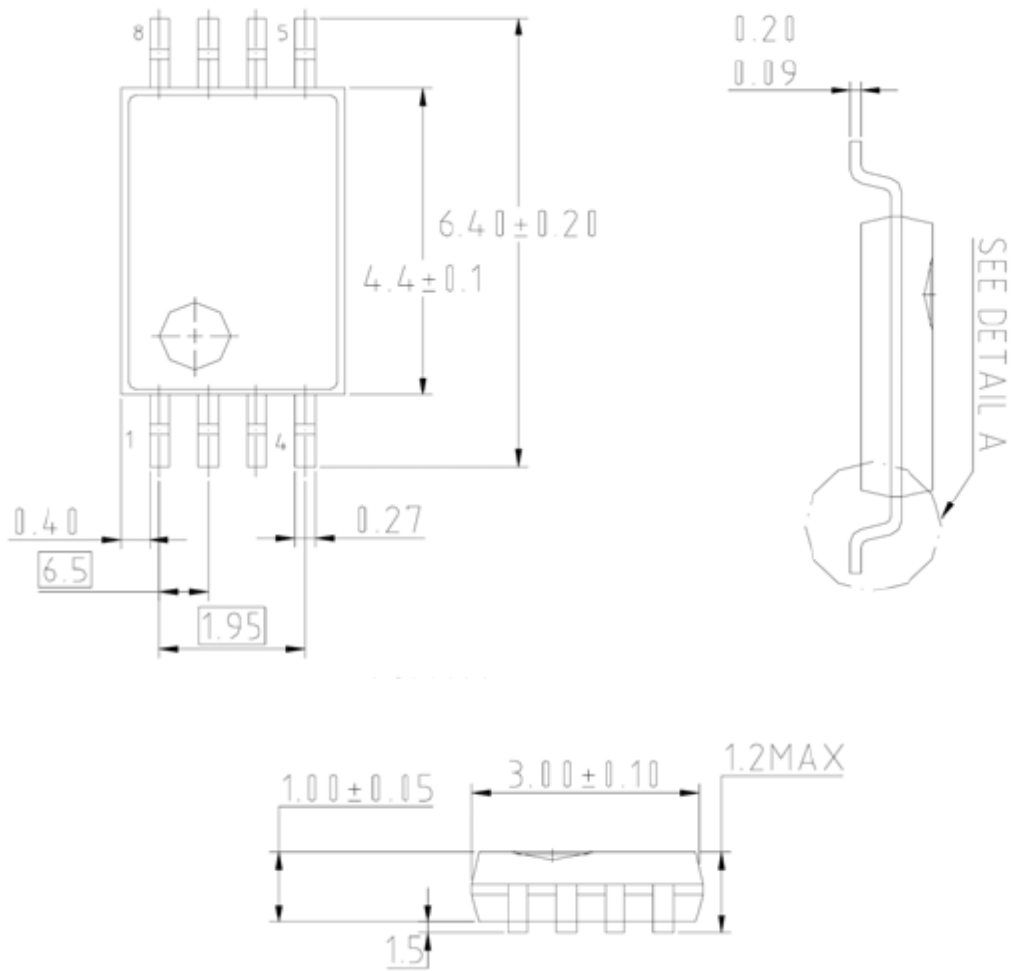


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## Packing Information

### TSSOP-8



Unit: mm

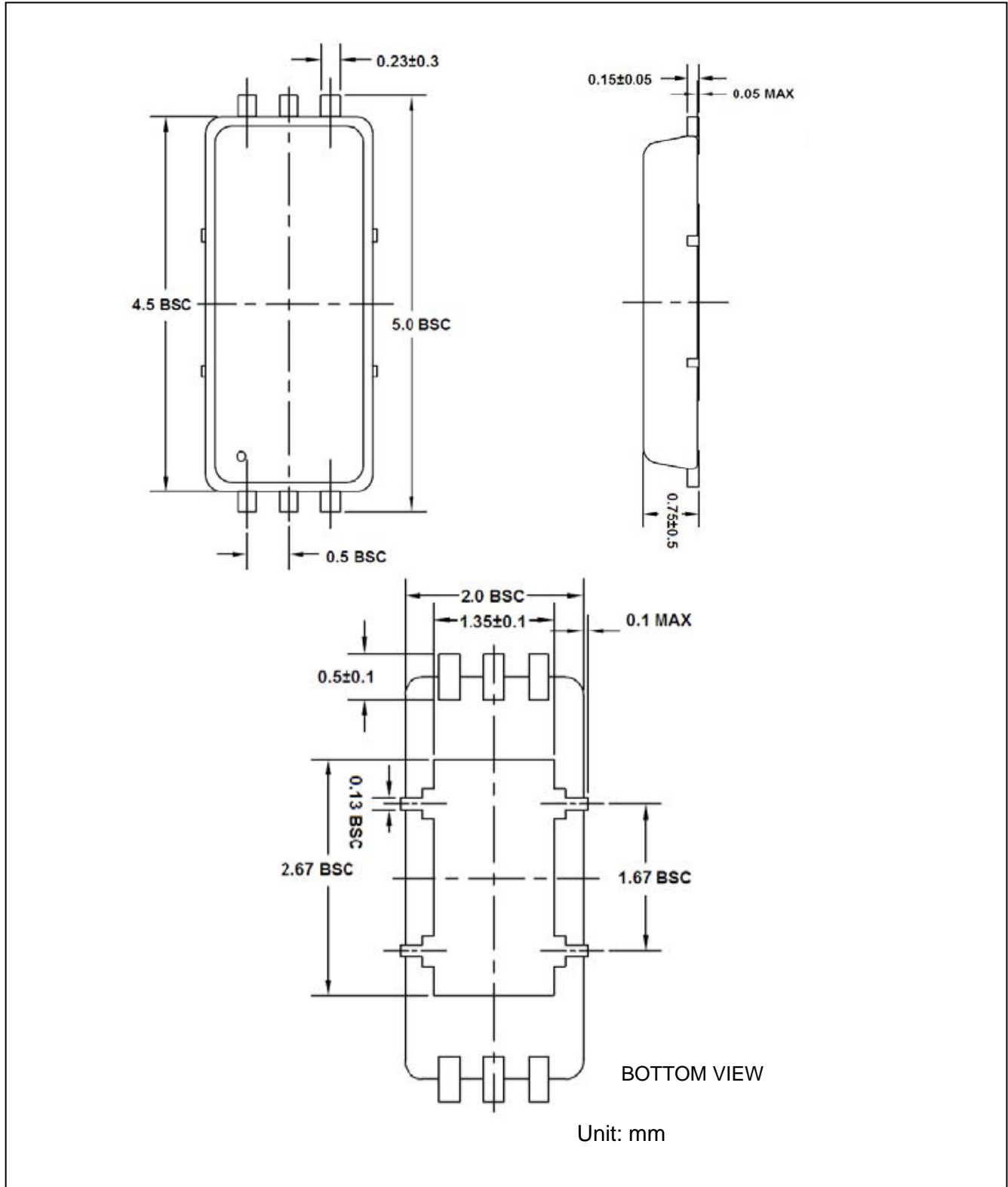


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## Packing Information

DFN2\*5







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### Notes

ACE does not assume any responsibility for use as critical components in life support devices or systems without the express written approval of the president and general counsel of ACE Electronics Co., LTD. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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